
Plasma Potential Determination in RF Capacitively Coupled Plasma by Measuring Electrode Voltage.

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Introduction

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Introduction

Dealey Plaza in the historic West End district of downtown Dallas, Texas



The assassination site;
the mark on the road where John F.
Kennedy was hit.



The Texas School Book Depository;
at the rooftop of that building, the
assassin shot at JFK.

Background

Plasma potential V_p ··· Decision of electron temperature,
Ion accelerations between bulk plasma
and sheaths

Measurement of V_p
→ **Probe diagnostics**

<u>Advantage</u>	<u>Disadvantage</u>
Simplicity	Plasma perturbations

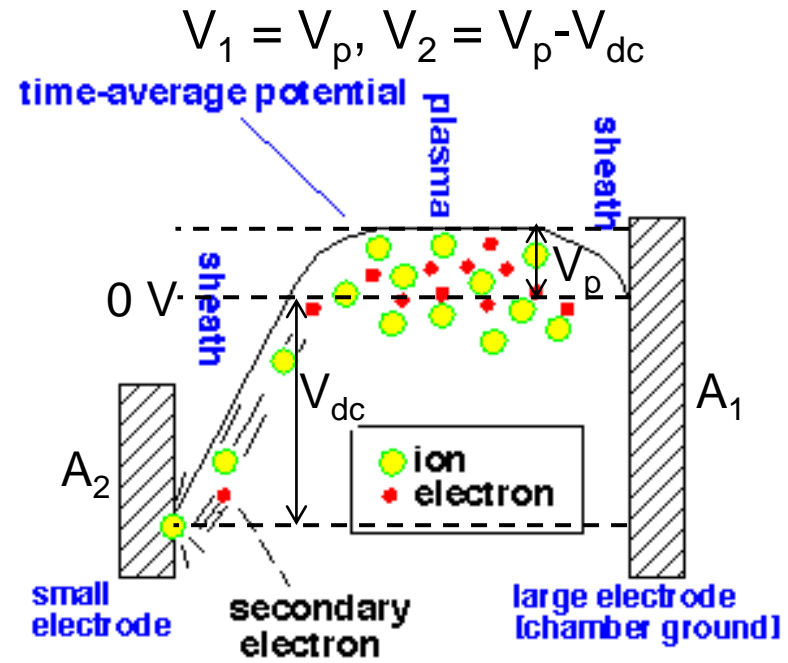
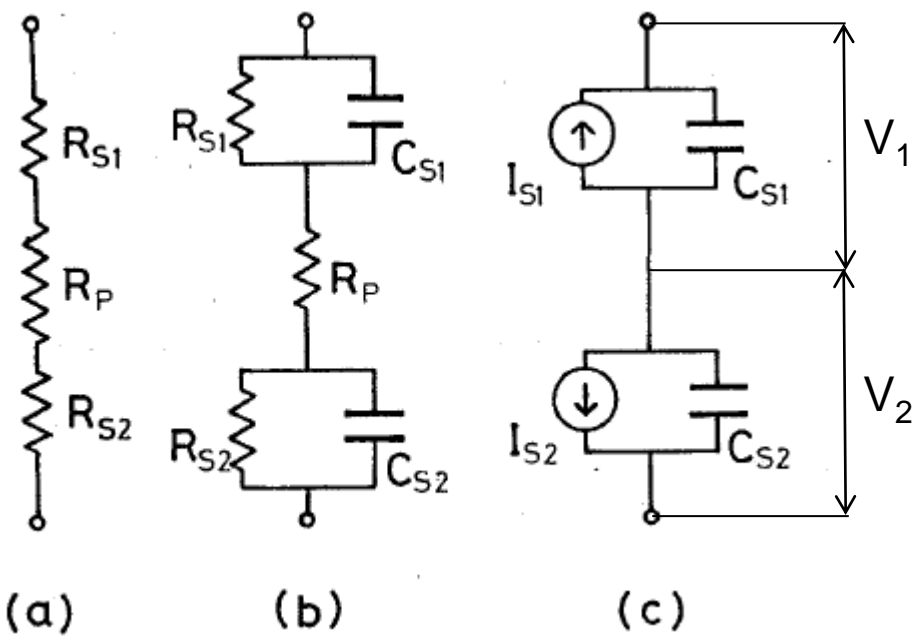


Noncontact measurement of V_p
→ **Measurement of electrode voltage**

Electrode voltage = DC self bias voltage (V_{dc}) + RF voltage (V_{rf})
(V_{dc} ··· Decision of ion energy in the sheaths)

Relation between V_{dc} and V_p

Plasma Equivalent Circuits



(a) DC or low frequency plasma, (b) High frequency plasma, and (c) Simplification of (b) by considering $R_p \ll R_{S1}, R_{S2}$, and most ions moving to electrodes

Potential diagram of V_p and V_{dc} [1]

$$\frac{V_1}{V_2} = \left(\frac{A_2}{A_1} \right)^a \quad (a \leq 2.5)^{[2]} \quad (1)$$

Substituting $V_1 = V_p$, $V_2 = V_p - V_{dc}$ in the equation (1) and arranging, we obtain

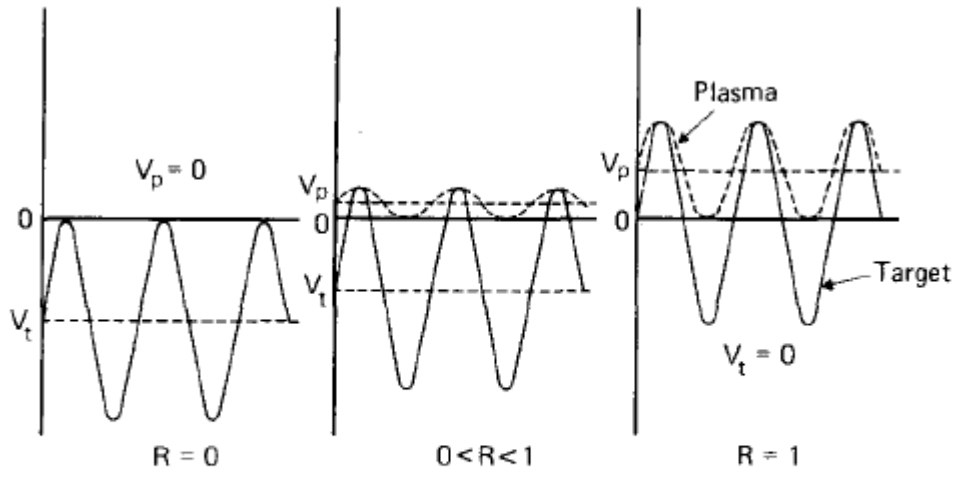
$$V_p = \frac{\left(\frac{A_2}{A_1} \right)^a}{\left(\frac{A_2}{A_1} \right)^a - 1} V_{dc} \quad (2)$$

[1] http://timedomaincvd.com/CVD_Fundamentals/plasmas/capacitive_plasma.html

[2] Principles of Plasma Discharges and Materials Processing

Relation between electrode voltage and V_p

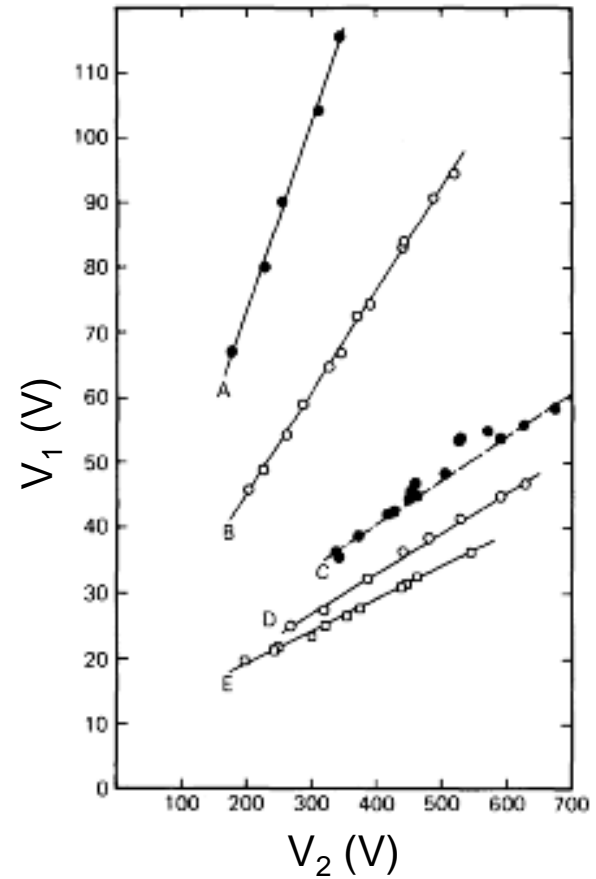
Experimental^[3]



$$R = A_2/A_1$$

FIG. 3. Approximate target and plasma voltage waveforms in a glow discharge with grounded walls (R is the ratio of target area to wall area).

We can find more accurate V_p by comparing one calculated from V_{dc} with one obtained from electrode voltage waveforms.



$$V_1 = V_p, \quad V_2 = V_p - V_t$$

$$\frac{V_1}{V_2} = \left(\frac{A_2}{A_1} \right)^a$$

($0.98 < a < 1.4$ when $0.09 < A_2/A_1 < 0.29$.)

[3] J. W. Coburn and K. Eric, J. Appl. Phys. **43** 4965 (1972).

Objective

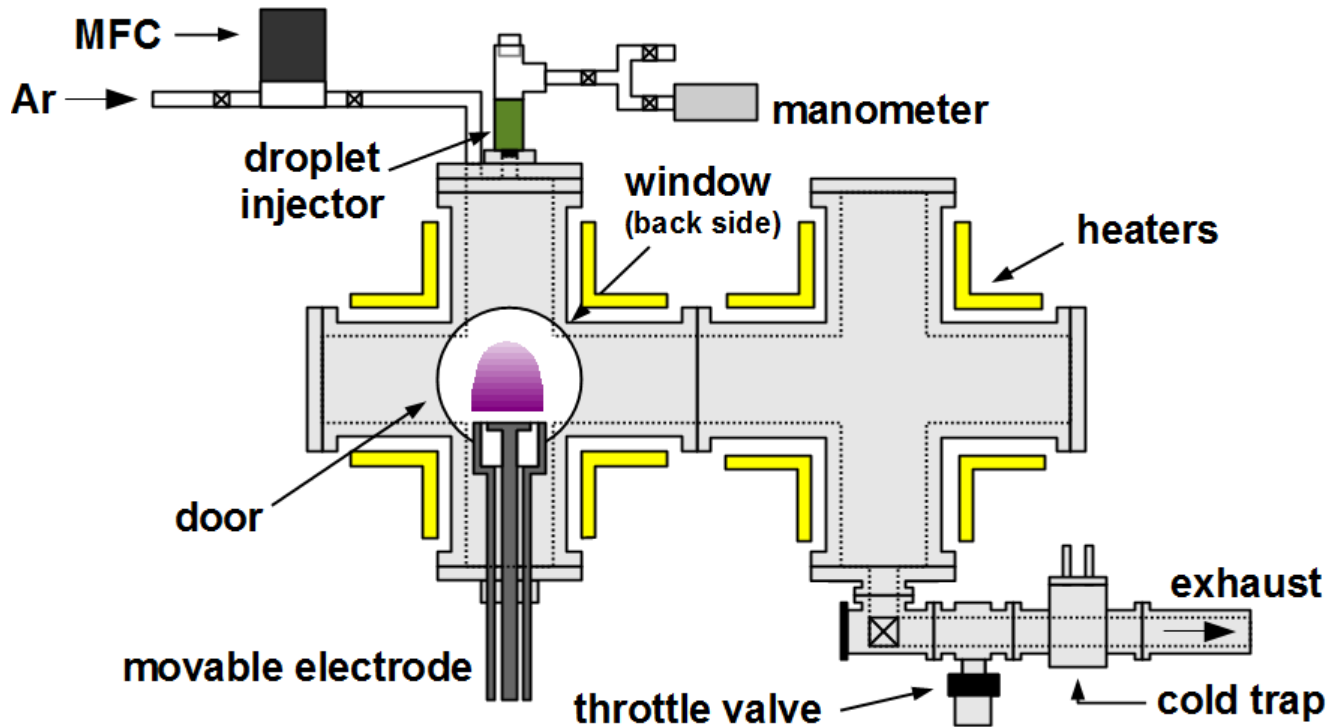
➤ V_{dc} measurements

- Construction of a circuit to measure DC component.
- Dependence of V_{dc} as a function of the electrode position.
- V_p calculation from outputs

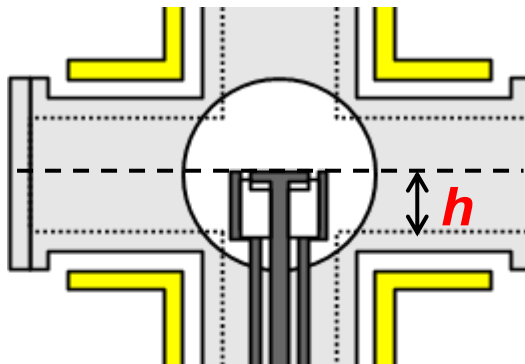
➤ V_{rf} measurements

- Construction of a voltage divider circuit
- Dependence of V_p as a function of the electrode position.

Experimental



Liquid injection plasma system



Ar gas flow rate : 20 sccm

RF power: 1 - 20 W Gas pressure : 16 Pa

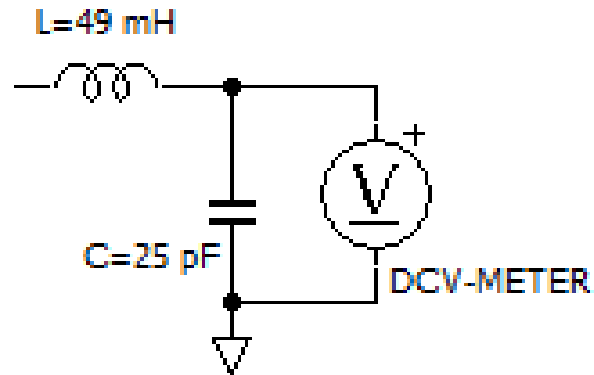
h (the electrode position) : 0, 2.5, 5.0 cm

A_2/A_1 : 0.017 ($h = 0$ cm), 0.015 ($h = 2.5, 5.0$ cm)

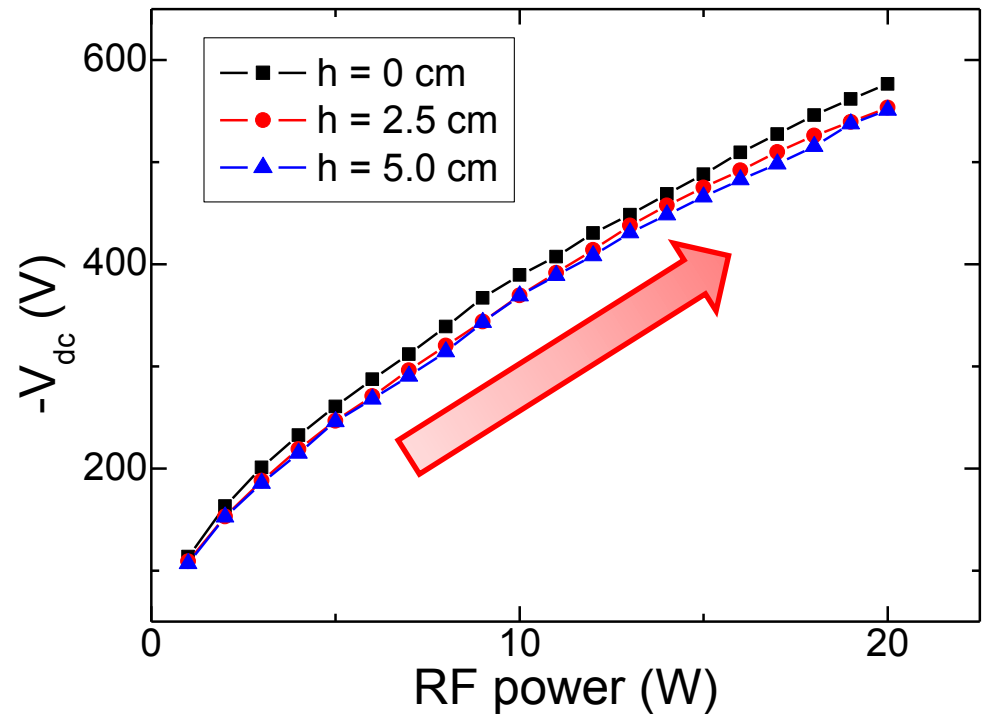
A_1 : Area of the grounded chamber

A_2 : Area of the energized electrode

Dependence of V_{dc} on the electrode position



Circuit diagram to measure DC component



Dependence of V_{dc} on h as a function of RF power

- Increase in $|V_{dc}| \rightarrow$ Increase in discharge voltage
- Decrease slightly in $|V_{dc}|$ with changing h

V_p calculation with V_{dc}

$$\frac{V_1}{V_2} = \frac{C_{sh2}}{C_{sh1}} = \frac{A_2 s_1}{A_1 s_2}$$

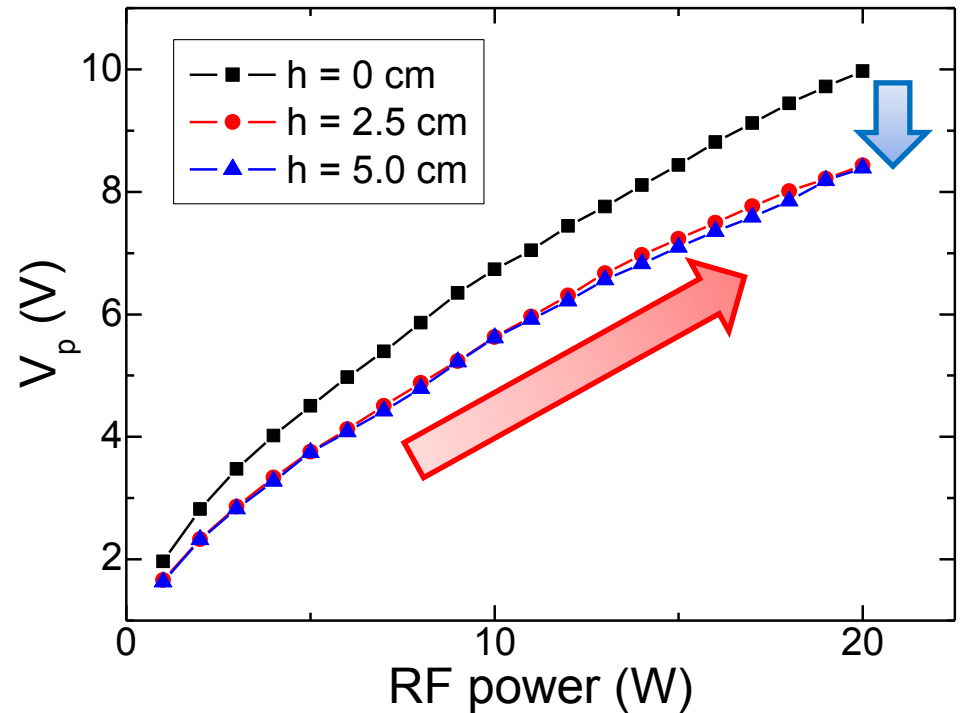
C_{sh1} , C_{sh2} : sheath capacitances
 s_1 , s_2 : sheath thicknesses

In RF plasma, ion sheaths can't follow the RF voltage.

→ $s_1/s_2 \sim 1$ (also as reported^[3])

→ In the equation (2), it is assumed that $a = 1$.

$$V_p = \frac{\frac{A_2}{A_1}}{\frac{A_2}{A_1} - 1} V_{dc} \quad (2)'$$



Dependence of V_p on h as a function of RF power

Decreases in averaged V_p and $|V_{dc}|$ with changing h
→ Decrease in the electron temperature

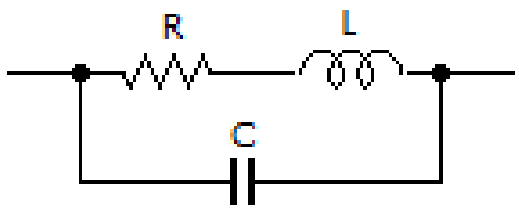
Measurement of electrode voltage

Methods of measuring electrode voltage ($V_{rf} + V_{dc}$)

High voltage probe
Voltage divider



RF high voltage have to be divided into measurable voltages.
→ Voltage divider circuit



Equivalent circuit of general electric element for RF voltage

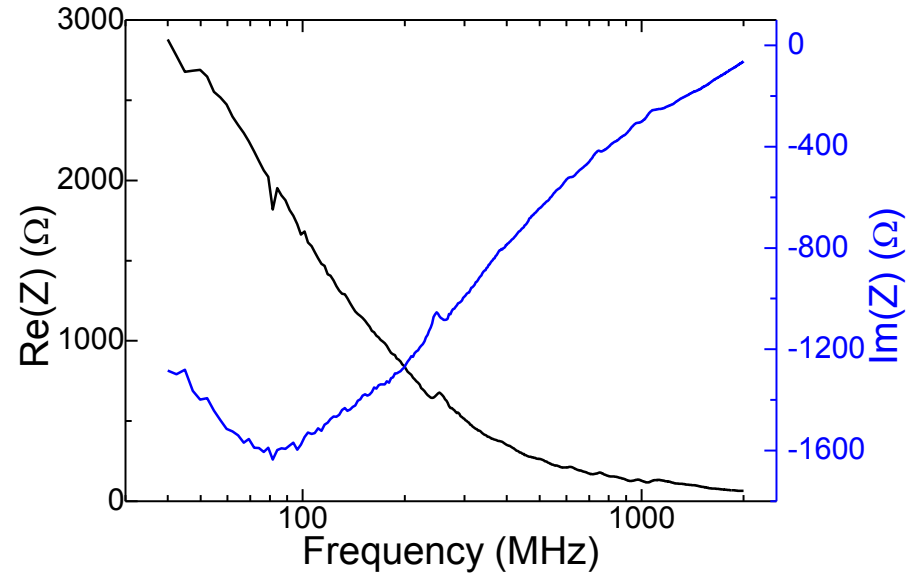
ex. $R=1\text{ M}\Omega$, $L=0.1\text{ }\mu\text{H}$, $C=0.1\text{ pF}$

$f=10\text{ Hz}$

→ $j\omega L \ll R$, $1/j\omega C \gg R \rightarrow Z \sim R$

$f=10\text{ MHz}$

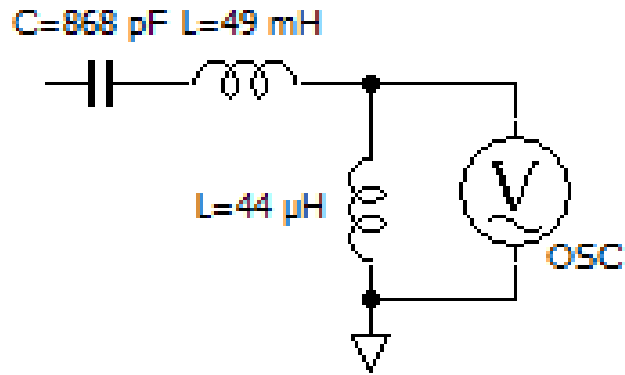
→ $j\omega L \ll R$, $1/j\omega C \ll R \rightarrow Z \sim 1/j\omega C$



Dependence of 5.4 MΩ resistor on frequency

For RF voltage, influences of inductance and capacitance are critical.

Evaluation of V_p by measuring V_{rf}



RF voltage divider circuit

Theoretical

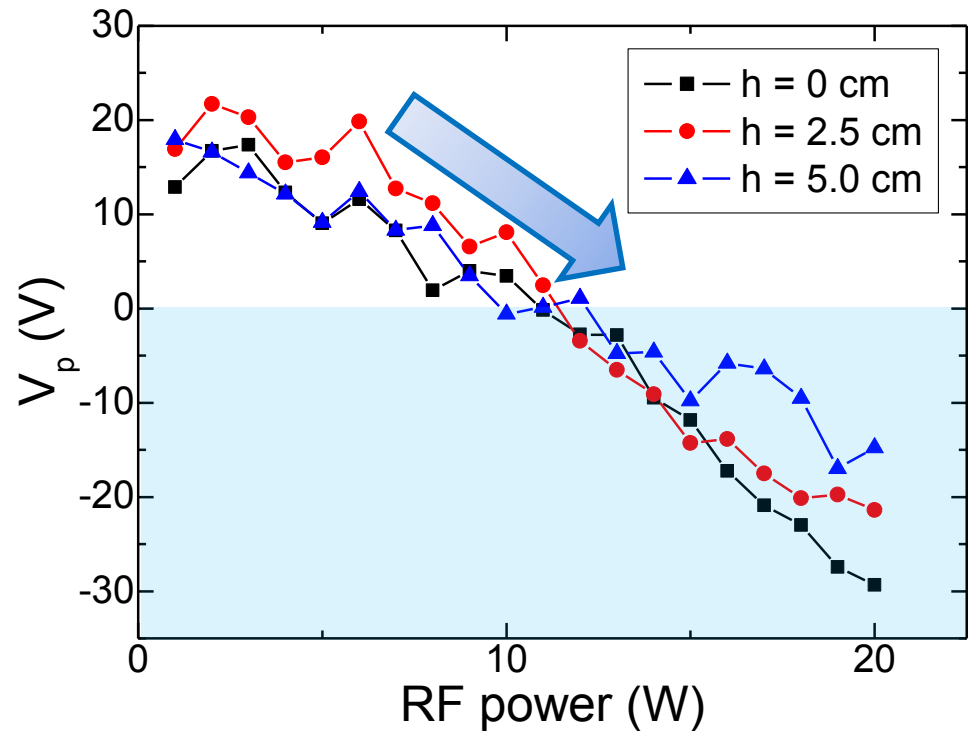
$$V_{rf} \approx 1114 * V_O$$

V_{rf} : amplitude of RF discharge voltage
 V_O : amplitude of measured RF voltage

Actual measurement

$$V_{rf} \approx 71 * V_O$$

➡ Incorrect values on capacitors and inductors.



Dependence of V_p on h as a function of RF power

The behaviors of V_p were obviously incorrect.

Induced voltages or RF noises in MN
 → Inaccurate V_{rf}

Summary

V_p in the RF capacitively coupled plasma was determined by measuring V_{dc} with changing the electrode position.

- Decreases in averaged V_p and $|V_{dc}|$ with changing h
→ Decrease in the electron temperature

V_p was determined by measuring V_{rf} with changing the electrode position by using a voltage divider circuit.

- Correct V_p was hardly obtained because of induced voltages or RF noises.

Future works

- More accurate measurements of V_{rf} by getting circuit lines as short as possible.
- Identification of frequency dependencies of electric elements.
- Comparisons of electron density, electron temperature, and V_p with other techniques.

*Thank you for your kind
help and support!*